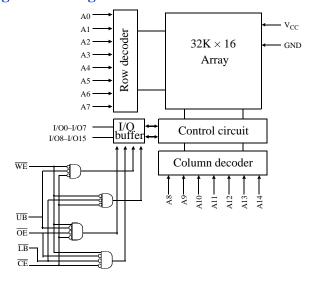


#### **Features**

- Industrial and commercial temperature
- Organization: 32,768 words × 16 bits
- Center power and ground pins
- High speed
- 10/12/15/20 ns address access time
- 5, 6, 7, 8 ns output enable access time
- Low power consumption: ACTIVE
- 288 mW / max @ 10 ns
- Low power consumption: STANDBY
- 18 mW / max CMOS
- 6T 0.18m CMOS Technology

- Easy memory expansion with  $\overline{CE}$ ,  $\overline{OE}$  inputs
- TTL-compatible, three-state I/O
- 44-pin JEDEC standard package
- 400 mil SOJ
- 400 mil TSOP 2
- ESD protection  $\geq$  2000 volts
- Latch-up current  $\geq$  200 mA

### Logic block diagram



### Pin arrangement

44-Pin SOJ, TSOP 2 (400 mil)

NC	44 A4 43 A5 42 A6 41 OE 40 UB 39 LB 38 VO15 37 VO13 36 VO13 35 VO2 32 VO11 31 VO10 30 VO2 29 VO8 28 NC 27 A7
WE 17	28 NC

#### **Selection guide**

	-10	-12	-15	-20	Unit
Maximum address access time	10	12	15	20	ns
Maximum output enable access time	5	6	7	8	ns
Maximum operating current	80	75	70	65	mA
Maximum CMOS standby current	5	5	5	5	mA



### **Functional description**

The AS7C3513B is a high performance CMOS 524,288-bit Static Random Access Memory (SRAM) device organized as 32,768 words  $\times$  16 bits. They are designed for memory applications where fast data access, low power, and simple interfacing are desired.

Equal address access and cycle times  $(t_{AA},\,t_{RC},\,t_{WC})$  of 10/12/15/20 ns with output enable access times  $(t_{OE})$  of 5, 6, 7, 8 ns are ideal for high performance applications. The chip enable input  $\overline{CE}$  permits easy memory expansion with multiple-bank memory systems.

When  $\overline{\text{CE}}$  is high, the device enters standby mode. If inputs are still toggling, the device consumes  $I_{SB}$  power. If the bus is static, then the full standby power is reached ( $I_{SB1}$ ). The AS7C3513B is guaranteed not to exceed 18mW power consumption under nominal full standby conditions.

A write cycle is accomplished by asserting write enable ( $\overline{WE}$ ), ( $\overline{UB}$ ) and/or ( $\overline{LB}$ ), and chip enable ( $\overline{CE}$ ). Data on the input pins I/O0 - I/O7, and/or I/O8 - I/O15, is written on the rising edge of  $\overline{WE}$  (write cycle 1) or  $\overline{CE}$  (write cycle 2). To avoid bus contention, external devices should drive I/O pins only after outputs have been disabled with output enable ( $\overline{OE}$ ) or write enable ( $\overline{WE}$ ).

A read cycle is accomplished by asserting output enable  $(\overline{OE})$ ,  $(\overline{UB})$  and  $(\overline{LB})$ , and chip enable  $(\overline{CE})$ , with write enable  $(\overline{WE})$  high. The chips drive I/O pins with the data word referenced by the input address. When either chip enable or output enable is inactive, or write enable is active, or  $(\overline{UB})$  and  $(\overline{LB})$ , output drivers stay in high-impedance mode.

The devices provide multiple center power and ground pins, and separate byte enable controls, allowing individual bytes to be written and read.  $\overline{LB}$  controls the lower bits, I/O0 - I/O7, and  $\overline{UB}$  controls the higher bits, I/O8 - I/O15.

All chip inputs and outputs are TTL-compatible. The AS7C3513B is packaged in common industry standard packages.

#### **Absolute maximum ratings**

Parameter	Symbol	Min	Max	Unit
Voltage on $V_{CC}$ relative to GND	$V_{t1}$	-0.50	+5.0	V
Voltage on any pin relative to GND	$V_{t2}$	-0.50	V <sub>CC</sub> +0.50	V
Power dissipation	$P_{\mathrm{D}}$	_	1.0	W
Storage temperature (plastic)	$T_{stg}$	-65	+150	° C
Ambient temperature with V <sub>CC</sub> applied	T <sub>bias</sub>	-55	+125	° C
DC current into outputs (low)	I <sub>OUT</sub>	_	20	mA

NOTE: Stresses greater than those listed under *Absolute Maximum Ratings* may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions outside those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect reliability.

#### Truth table

CE	WE	<del>OE</del>	LB	<del>UB</del>	I/O0–I/O7	I/O8–I/O15	Mode
Н	X	X	X	X	High Z	High Z	Standby (I <sub>SB</sub> , I <sub>SBI</sub> )
L	Н	L	L	Н	D <sub>OUT</sub>	High Z	Read I/O0–I/O7 (I <sub>CC</sub> )
L	Н	L	Н	L	High Z	D <sub>OUT</sub>	Read I/O8–I/O15 (I <sub>CC</sub> )
L	Н	L	L	L	D <sub>OUT</sub>	D <sub>OUT</sub>	Read I/O0–I/O15 (I <sub>CC</sub> )
L	L	X	L	L	D <sub>IN</sub>	D <sub>IN</sub>	Write I/O0–I/O15 (I <sub>CC</sub> )
L	L	X	L	Н	D <sub>IN</sub>	High Z	Write I/O0–I/O7 (I <sub>CC</sub> )
L	L	X	Н	L	High Z	D <sub>IN</sub>	Write I/O8–I/O15 (I <sub>CC</sub> )
L L	H X	H X	X H	X H	High Z	High Z	Output disable (I <sub>CC</sub> )

 $Key: X = Don't \ care; \ L = Low; \ H = High$ 



## **Recommended operating conditions**

Parameter		Symbol	Min	Typical	Max	Unit
Supply voltage	$V_{CC}$	3.0	3.3	3.6	V	
Investment and	$V_{IH}$	2.0	-	V <sub>CC</sub> + 0.5		
Input voitage	Input voltage			-	0.8	V
Al.:	commercial	$T_{A}$	0	-	70	°C
Ambient operating temperature	industrial	$T_{A}$	-40	-	85	° C

 $V_{IL} = \text{-}1.0 \text{V}$  for pulse width less than 5ns

## DC operating characteristics (over the operating range) $^{I}$

			-1	-10 -12		2	-15		-20		
Parameter	Sym	Test conditions	Min	Max	Min	Max	Min	Max	Min	Max	Unit
Input leakage current	$\mid I_{LI} \mid$	$V_{CC}$ = Max $V_{IN}$ = GND to $V_{CC}$	ı	1	١	1	ı	1	ı	1	μΑ
Output leakage current	I <sub>LO</sub>	$V_{CC} = Max$ $V_{OUT} = GND \text{ to } V_{CC}$	ı	1	ı	1	ı	1	ı	1	μA
Operating power supply current	$I_{CC}$	$V_{CC} = Max$ , $\overline{CE} \le V_{IL}$ $f = f_{Max}$ , $I_{OUT} = 0mA$	I	80	I	75	I	70	I	65	mA
G. 11	$I_{SB}$	$V_{CC} = Max, \overline{CE} \ge V_{IH}$ $f = f_{Max}$	ı	30	ı	25	I	20	ı	20	mA
Standby power supply current	$I_{SB1}$	$\begin{split} &V_{CC} = Max, \overline{CE} \geq V_{CC} 0.2V \\ &V_{IN} \leq 0.2V \text{ or } V_{IN} \geq V_{CC} 0.2V, \\ &f = 0 \end{split}$	I	5	ı	5	ı	5	ı	5	mA
Output volte co	V <sub>OL</sub>	$I_{OL}$ = 8 mA, $V_{CC}$ = Min	_	0.4	-	0.4	_	0.4	_	0.4	V
Output voltage	V <sub>OH</sub>	$I_{OH}$ = -4 mA, $V_{CC}$ = Min	2.4	_	2.4	_	2.4	_	2.4	_	V

# Capacitance (f = 1MHz, $T_a = 25^{\circ} C$ , $V_{CC} = NOMINAL$ )<sup>2</sup>

Parameter	Symbol	Signals	Test conditions	Max	Unit
Input capacitance	C <sub>IN</sub>	$A, \overline{CE}, \overline{WE}, \overline{OE}, \overline{LB}, \overline{UB}$	$V_{in} = 0V$	5	pF
I/O capacitance	$C_{I/O}$	I/O	$V_{in} = V_{out} = 0V$	7	pF

 $V_{IH\,=}\,V_{CC}\,+\,1.5V$  for pulse width less than 5ns



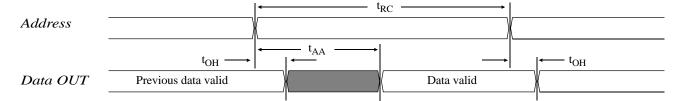
## Read cycle (over the operating range) 3,9

		-1	10	-1	12	-1	15	-2	20		
Parameter	Symbol	Min	Max	Min	Max	Min	Max	Min	Max	Unit	Notes
Read cycle time	t <sub>RC</sub>	10	_	12	_	15	_	20	_	ns	
Address access time	$t_{AA}$	_	10	-	12	_	15	_	20	ns	3
Chip enable (CE) access time	t <sub>ACE</sub>	_	10	-	12	_	15	_	20	ns	3
Output enable (OE) access time	t <sub>OE</sub>	_	5	-	6	_	7	_	8	ns	
Output hold from address change	t <sub>OH</sub>	3	-	3	-	3	-	3	-	ns	5
CE low to output in low Z	t <sub>CLZ</sub>	3	_	3	_	3	_	3	_	ns	4,5
CE high to output in high Z	t <sub>CHZ</sub>	_	3	-	3	_	4	_	5	ns	4,5
OE low to output in low Z	t <sub>OLZ</sub>	0	_	0	_	0	_	0	_	ns	4,5
Byte select access time	t <sub>BA</sub>	_	5	-	6	_	7	_	8	ns	
Byte select Low to low Z	t <sub>BLZ</sub>	0	_	0	_	0	_	0	_	ns	4,5
Byte select High to high Z	t <sub>BHZ</sub>	_	5	-	6	_	6	_	8	ns	4,5
OE high to output in high Z	t <sub>OHZ</sub>	_	5	-	6	_	7	_	8	ns	4,5
Power up time	$t_{\mathrm{PU}}$	0	_	0	_	0	_	0	_	ns	4,5
Power down time	t <sub>PD</sub>	_	10	-	12	_	15		20	ns	4,5

## **Key to switching waveforms**

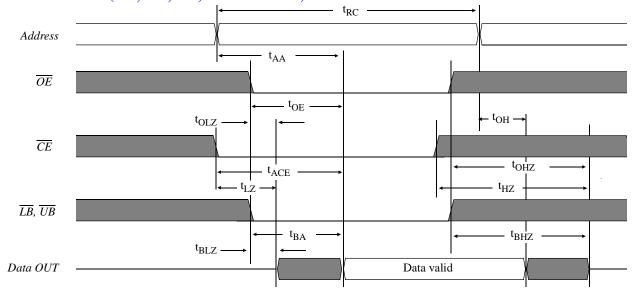
Rising input Falling input Undefined output/don't care

## Read waveform 1 (address controlled)<sup>3,6,7,9</sup>





## Read waveform 2 ( $\overline{CE}$ , $\overline{OE}$ , UB, LB controlled)<sup>3,6,8,9</sup>

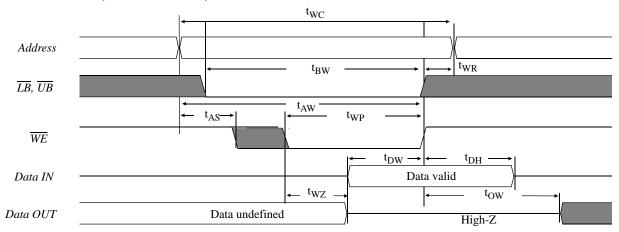


## Write cycle (over the operating range) $^{II}$

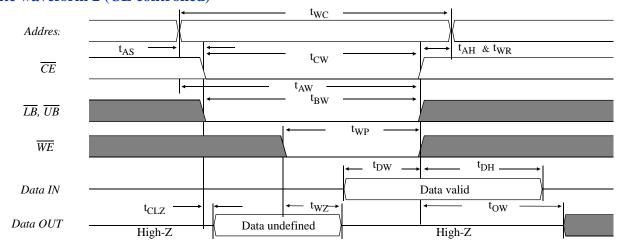
		-1	10	-1	12	-1	15	-2	20		
Parameter	Symbol	Min	Max	Min	Max	Min	Max	Min	Max	Unit	Notes
Write cycle time	t <sub>WC</sub>	10	_	12	_	15	-	20	-	ns	
Chip enable (CE) to write end	$t_{CW}$	8	_	9	_	10	-	12	-	ns	
Address setup to write end	$t_{AW}$	8	_	9	_	10	-	12	-	ns	
Address setup time	$t_{AS}$	0	_	0	-	0	_	0	-	ns	
Write pulse width	$t_{WP}$	7	_	8	-	9	_	12	-	ns	
Write recovery time	$t_{WR}$	0	_	0	_	0	-	0	-	ns	
Address hold from end of write	t <sub>AH</sub>	0	_	0	-	0	_	0	-	ns	
Data valid to write end	$t_{DW}$	5	_	6	-	8	_	10	-	ns	
Data hold time	t <sub>DH</sub>	0	_	0	_	0	_	0	_	ns	5
Write enable to output in high Z	$t_{ m WZ}$	_	5	_	6	_	7	-	8	ns	4,5
Output active from write end	t <sub>OW</sub>	1	_	1	-	1	_	2	_	ns	4,5
Byte select low to end of write	$t_{\mathrm{BW}}$	7	_	8	_	9	_	9	_	ns	



# Write waveform $1(\overline{\text{WE}} \text{ controlled})^{II}$



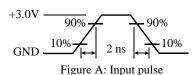
## Write waveform 2 ( $\overline{\text{CE}}$ controlled)<sup>II</sup>





#### **AC** test conditions

- Output load: see Figure B.
- Input pulse level: GND to 3.0V. See Figure A.
- Input rise and fall times: 2 ns. See Figure A.
- Input and output timing reference levels: 1.5V.



Thevenin equivalent:

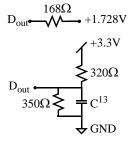


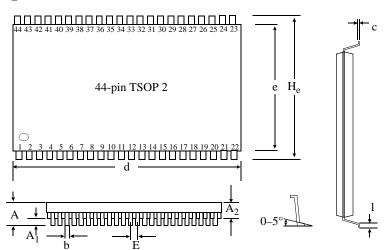
Figure B: 3.3V Output load

### **Notes**

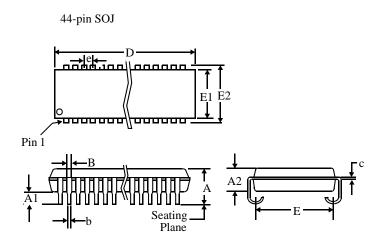
- 1 During  $V_{CC}$  power-up, a pull-up resistor to  $V_{CC}$  on  $\overline{CE}$  is required to meet  $I_{SB}$  specification.
- 2 This parameter is sampled, but not 100% tested.
- 3 For test conditions, see AC Test Conditions, Figures A and B.
- 4 These parameters are specified with  $C_L = 5 pF$ , as in Figure B. Transition is measured  $\pm 500 mV$  from steady-state voltage.
- 5 This parameter is guaranteed, but not 100% tested.
- 6 WE is High for read cycle.
- 7  $\overline{\text{CE}}$  and  $\overline{\text{OE}}$  are Low for read cycle.
- 8 Address valid prior to or coincident with  $\overline{\text{CE}}$  transition Low.
- 9 All read cycle timings are referenced from the last valid address to the first transitioning address.
- 10 Not applicable.
- 11 All write cycle timings are referenced from the last valid address to the first transitioning address.
- 12 Not applicable.
- 13 C=30pF, except on High Z and Low Z parameters, where C=5pF.



## **Package dimensions**



	<b>44-pin</b> ′	TSOP 2				
Symbol	Min (mm)	Max (mm)				
A		1.2				
A <sub>1</sub>	0.05	0.15				
$A_2$	0.95	1.05				
b	0.3	0.45				
с	0.12	0.21				
d	18.31	18.52				
e	10.06	10.26				
$H_{e}$	11.68	11.94				
E	0.80 (typical)					
1	0.40	0.60				



	44-pin SOJ 400 mil							
Symbol	Min	Max						
A	0.128	0.148						
A1	0.025	-						
A2	0.105	0.115						
В	0.026	0.032						
b	0.015	0.020						
С	0.007	0.013						
D	1.120	1.130						
E	0.370	NOM						
E1	0.395	0.405						
E2	0.435	0.445						
e	0.050	NOM						



## **Ordering codes**

Package\Access time		10 ns 12 ns		15 ns	20 ns
Plastic SOJ, 400	Commercial	AS7C3513B-10JC	AS7C3513B-12JC	AS7C3513B-15JC	AS7C3513B-20JC
mil	Industrial	AS7C3513B-10JI	AS7C3513B-12JI	AS7C3513B-15JI	AS7C3513B-20JI
TSOP 2,	Commercial	AS7C3513B-10TC	AS7C3513B-12TC	AS7C3513B-15TC	AS7C3513B-20TC
18.4×10.2 mm	Industrial	AS7C3513B-10TI	AS7C3513B-12TI	AS7C3513B-15TI	AS7C3513B-20TI

Note:

Add suffix 'N' to the above part number for lead free parts (Ex. AS7C3513B-10JCN)

### **Part numbering system**

AS7C	3	513B	-XX	X	C	X
SRAM prefix	Voltage: 3.3V CMOS	Device number	Access time	Package: J = SOJ 400 mil T =TSOP 2 18.4×10.2 mm	Temperature range: C = Commercial, 0°C to 70°C I = Industrial, -40°C to 85°C	N=Lead Free Part





Alliance Semiconductor Corporation 2575, Augustine Drive, Santa Clara, CA 95054 Tel: 408 - 855 - 4900

Fax: 408 - 855 - 4999

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